

Notice of References Cited	Application/Control No. 10/747,620	Applicant(s)/Patent Under Reexamination HAN, JAE WON	
	Examiner Kin-Chan Chen	Art Unit 1765	Page 1 of 1

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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